Chinastandards.org

CCS L55

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 21147.1-2016

Military integrated circuits - Electromagnetic emission measurement methods - Part 1: General conditions and definitions

军用集成电路电磁发射测量方法 第1部分：通用条件和定义

(English Translation)

Issued by: Ministry of Industry and Information Technology

Preview: page 1 of 3 shown, 14 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21147-1-2016

Chinastandards.org

Table of Contents

[Preview only]
1 Scope
2 Normative References
2.1 Terms
3 Terms and Definitions
4 Overview
4.1 General requirements
5 Technical Requirements
6 Calibration conditions
6.1 Environmental conditions
6.2 Measurement standards and other equipment
7 Calibration items and calibration methods
7.1 Calibration Items
7.2 Calibration method
8 Expression of calibration results
9 Recalibration interval

1 Foreword

SJ 21147.1-2016 is issued by Ministry of Industry and Information Technology.

It is one of 5 parts of the SJ 21147 series.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

2 Scope Preview

SJ 21147.1-2016 is filed under Chinese Standard Classification L55, in the field of electronic components and information technology.

This catalogue holds 1,191 other SJ standards without an ICS number.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

Preview: page 2 of 3 shown, 14 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21147-1-2016

3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 14 pages (approximate)

Chinese original: about 20,266 characters

4 Related standards

Other parts of this standard:

SJ 21147.2-2016 - Part 2: Radiation emission measurements - TEM cells and broadband TEM chamber

SJ 21147.3-2016 - Methods of measurement for electromagnetic emission of military integrated circuits - Part 3: Radiation emission measurements - Surface scanning

SJ 21147.4-2016 - Methods of measurement for electromagnetic emission of military integrated circuits - Part 4: Conducted emission measurements - 1omega /150omega direct coupling method

SJ 21147.5-2016 - Methods of measurement for electromagnetic emission of military integrated circuits - Part 5: Conducted emission measurements - Workbench Faraday cage method

Standards on related subjects:

GB/T 46280.2-2025 - Specification for chiplet interconnection interface - Part 2: Protocol layer technical requirements

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

5 Classification and status

Chinese Standard Classification (CCS): L 55

Prefix SJ: mandatory standard.

Preview: page 3 of 3 shown, 14 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21147-1-2016